

FDB3682 / FDP3682

N-Channel PowerTrench® MOSFET

100 V, 32 A, 36 mΩ

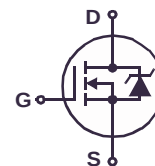
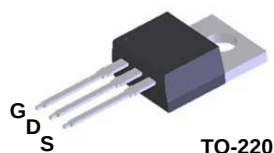
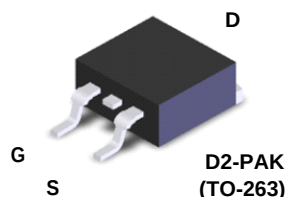
Features

- $R_{DS(on)} = 32 \text{ m}\Omega$ (Typ.) @ $V_{GS} = 10 \text{ V}$, $I_D = 32 \text{ A}$
- $Q_{G(tot)} = 18.5 \text{ nC}$ (Typ.) @ $V_{GS} = 10 \text{ V}$
- Low Miller Charge
- Low Q_{rr} Body Diode
- UIS Capability (Single Pulse and Repetitive Pulse)

Applications

- Consumer Appliances
- Synchronous Rectification
- Battery Protection Circuit
- Motor drives and Uninterruptible Power Supplies
- Micro Solar Inverter

Formerly developmental type 82755



MOSFET Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	FDB3682 / FDP3682	Unit
V_{DSS}	Drain to Source Voltage	100	V
V_{GS}	Gate to Source Voltage	± 20	V
I_D	Drain Current		
	Continuous ($T_C = 25^\circ\text{C}$, $V_{GS} = 10\text{V}$)	32	A
	Continuous ($T_C = 100^\circ\text{C}$, $V_{GS} = 10\text{V}$)	23	A
	Continuous ($T_{amb} = 25^\circ\text{C}$, $V_{GS} = 10\text{V}$, $R_{\theta JA} = 43^\circ\text{C/W}$)	6	A
	Pulsed	Figure 4	A
E_{AS}	Single Pulse Avalanche Energy (Note 1)	55	mJ
P_D	Power dissipation	95	W
	Derate above 25°C	0.63	W/ $^\circ\text{C}$
T_J, T_{STG}	Operating and Storage Temperature	-55 to 175	$^\circ\text{C}$

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance Junction to Case TO-220, TO-263, Max.	1.58	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-220, TO-263 (Note 2), Max.	62	$^\circ\text{C/W}$
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-263, 1in ² copper pad area, Max.	43	$^\circ\text{C/W}$

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB3682	FDB3682	TO-263	330mm	24mm	800 units
FDP3682	FDP3682	TO-220	Tube	N/A	50 units

Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Unit
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Off Characteristics

B_{VDSS}	Drain to Source Breakdown Voltage	$I_D = 250\mu\text{A}$, $V_{GS} = 0\text{V}$	100	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 80\text{V}$ $V_{GS} = 0\text{V}$ $T_C = 150^\circ\text{C}$	-	-	1	μA
I_{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20\text{V}$	-	-	± 100	nA

On Characteristics

$V_{GS(TH)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 250\mu\text{A}$	2	-	4	V
$r_{DS(ON)}$	Drain to Source On Resistance	$I_D = 32\text{A}$, $V_{GS} = 10\text{V}$	-	0.032	0.036	Ω
		$I_D = 16\text{A}$, $V_{GS} = 6\text{V}$,	-	0.040	0.060	
		$I_D = 32\text{A}$, $V_{GS} = 10\text{V}$, $T_C = 175^\circ\text{C}$	-	0.080	0.090	

Dynamic Characteristics

C_{ISS}	Input Capacitance	$V_{DS} = 25\text{V}$, $V_{GS} = 0\text{V}$, $f = 1\text{MHz}$	-	1250	-	pF
C_{OSS}	Output Capacitance		-	190	-	pF
C_{RSS}	Reverse Transfer Capacitance		-	45	-	pF
$Q_{g(TOT)}$	Total Gate Charge at 10V	$V_{GS} = 0\text{V}$ to 10V	-	18.5	28	nC
$Q_{g(TH)}$	Threshold Gate Charge	$V_{GS} = 0\text{V}$ to 2V	-	2.4	3.6	nC
Q_{gs}	Gate to Source Gate Charge	$V_{DD} = 50\text{V}$ $I_D = 32\text{A}$ $I_g = 1.0\text{mA}$	-	6.5	-	nC
Q_{gs2}	Gate Charge Threshold to Plateau		-	4.1	-	nC
Q_{gd}	Gate to Drain "Miller" Charge		-	4.6	-	nC

Resistive Switching Characteristics ($V_{GS} = 10\text{V}$)

t_{ON}	Turn-On Time	$V_{DD} = 50\text{V}$, $I_D = 32\text{A}$ $V_{GS} = 10\text{V}$, $R_{GS} = 16\Omega$	-	-	83	ns
$t_{d(ON)}$	Turn-On Delay Time		-	9	-	ns
t_r	Rise Time		-	46	-	ns
$t_{d(OFF)}$	Turn-Off Delay Time		-	26	-	ns
t_f	Fall Time		-	32	-	ns
t_{OFF}	Turn-Off Time		-	-	87	ns

Drain-Source Diode Characteristics

V_{SD}	Source to Drain Diode Voltage	$I_{SD} = 32\text{A}$	-	-	1.25	V
		$I_{SD} = 16\text{A}$	-	-	1.0	V
t_{rr}	Reverse Recovery Time	$I_{SD} = 32\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	55	ns
Q_{RR}	Reverse Recovery Charge	$I_{SD} = 32\text{A}$, $dI_{SD}/dt = 100\text{A}/\mu\text{s}$	-	-	90	nC

Notes:

1: Starting $T_J = 25^\circ\text{C}$, $L = 0.27\text{mH}$, $I_{AS} = 20\text{A}$.

2: Pulse Width = 100s

Typical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

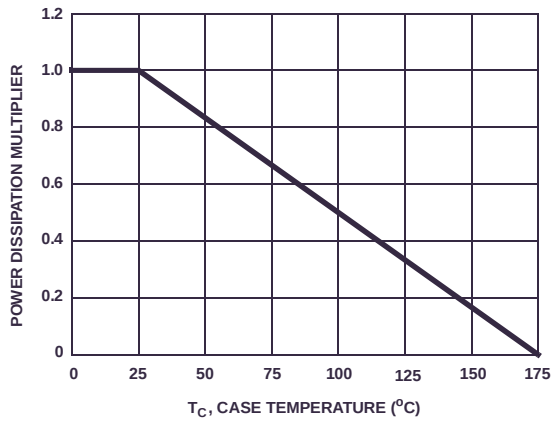


Figure 1. Normalized Power Dissipation vs Ambient Temperature

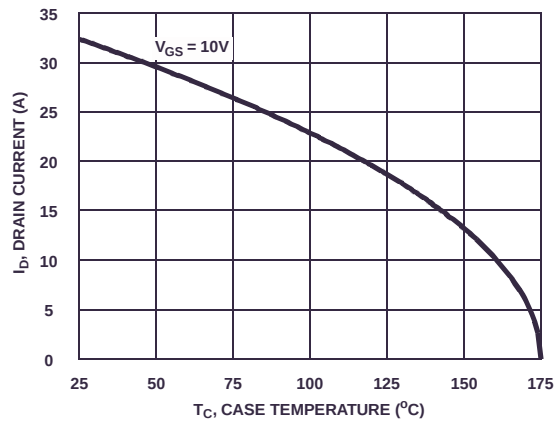


Figure 2. Maximum Continuous Drain Current vs Case Temperature

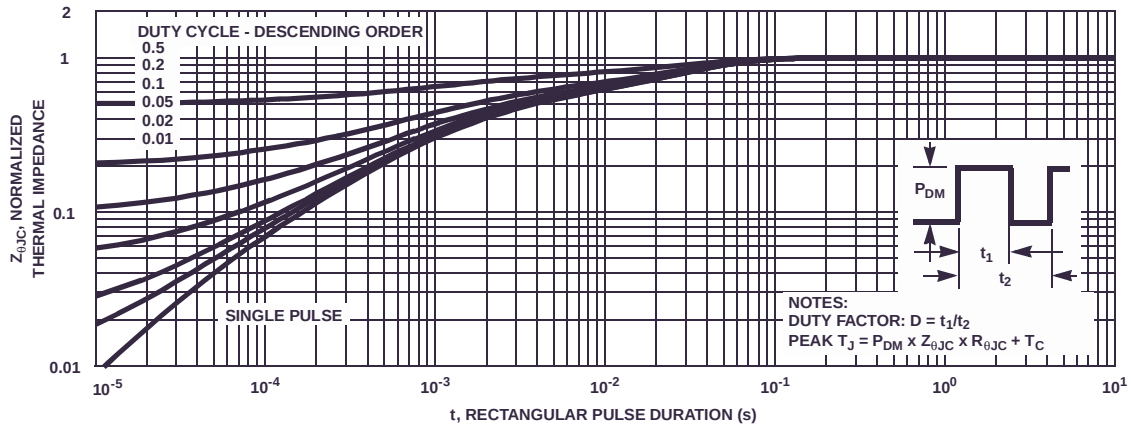


Figure 3. Normalized Maximum Transient Thermal Impedance

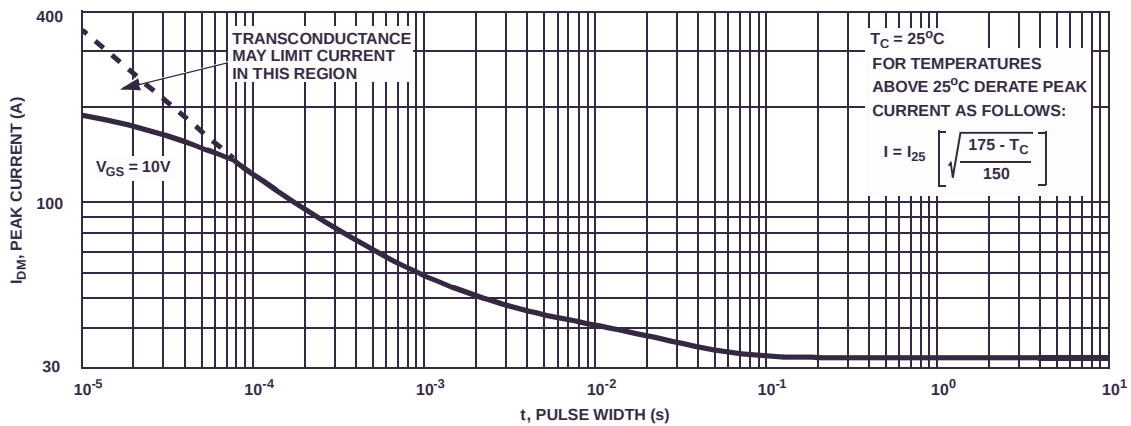


Figure 4. Peak Current Capability

Typical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

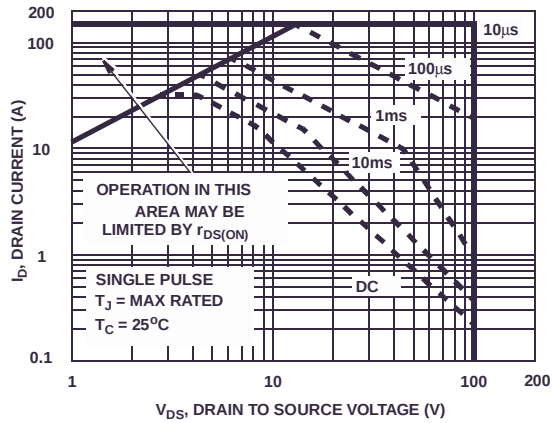
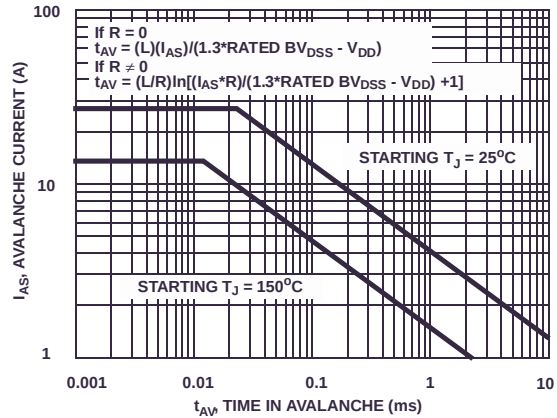


Figure 5. Forward Bias Safe Operating Area



NOTE: Refer to Fairchild Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching Capability

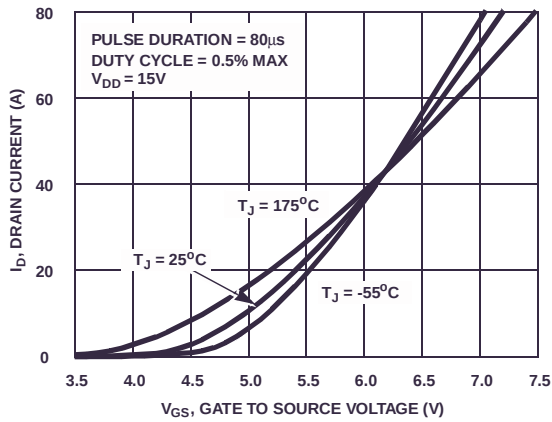


Figure 7. Transfer Characteristics

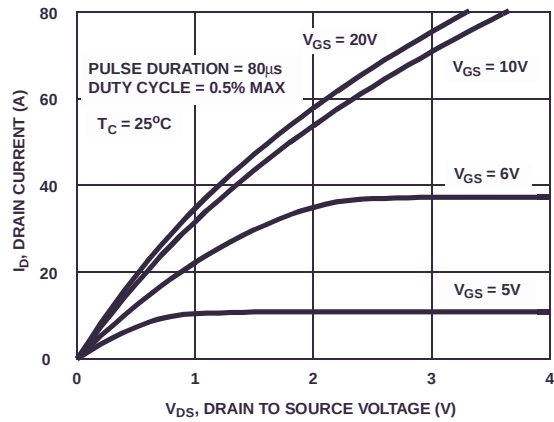


Figure 8. Saturation Characteristics

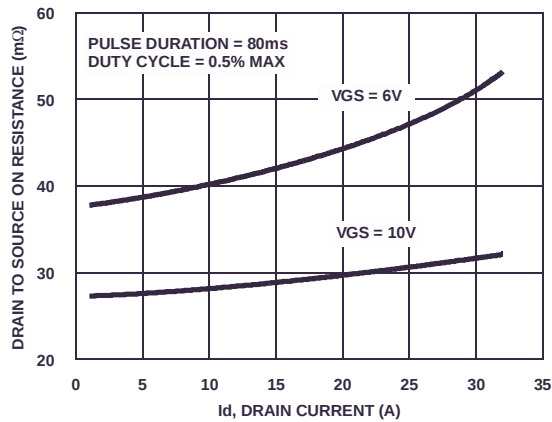


Figure 9. Drain to Source On Resistance vs Drain Current

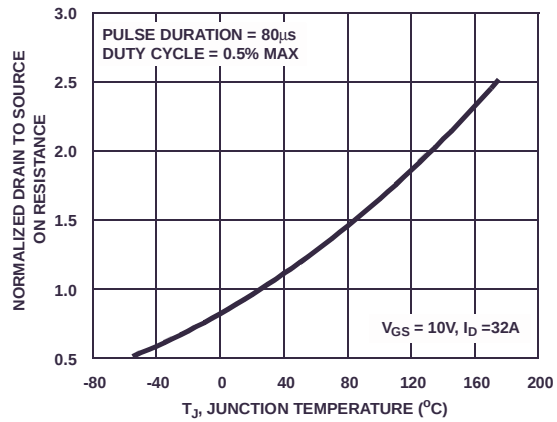


Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature

Typical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

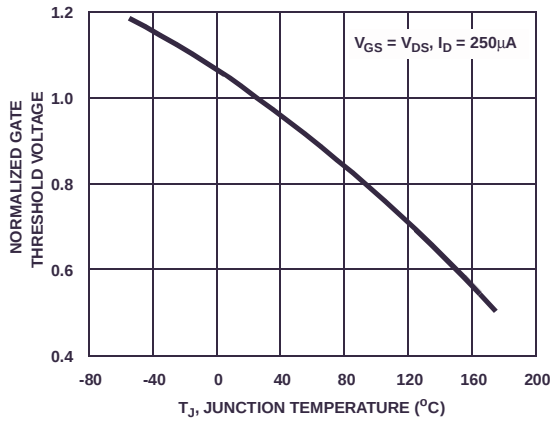


Figure 11. Normalized Gate Threshold Voltage vs Junction Temperature

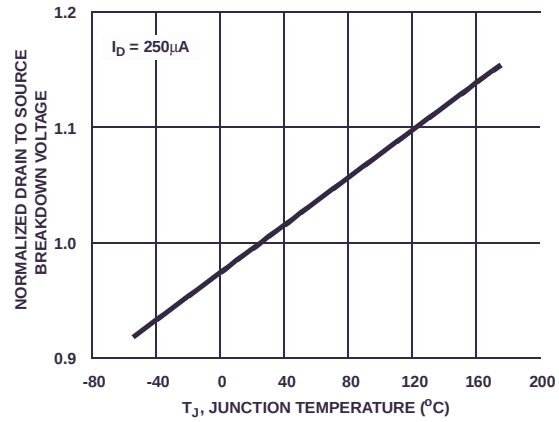


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

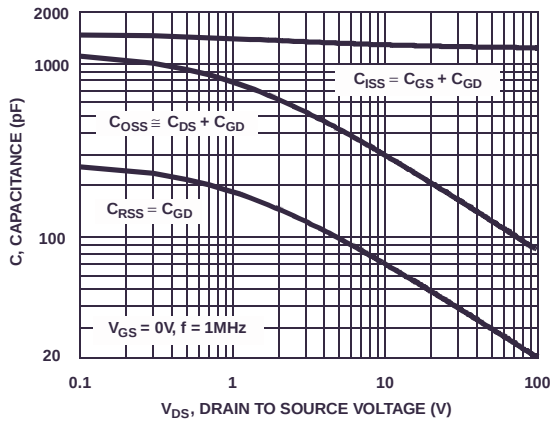


Figure 13. Capacitance vs Drain to Source Voltage

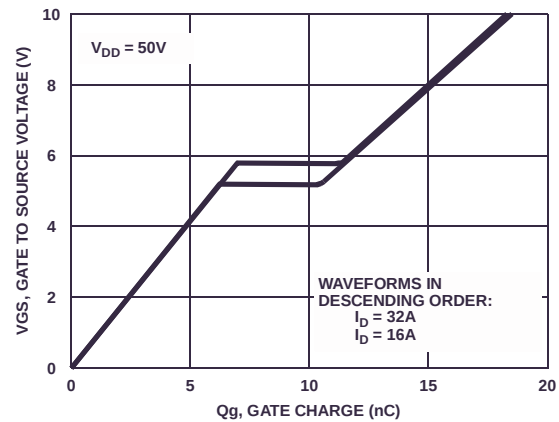


Figure 14. Gate Charge Waveforms for Constant Gate Currents

Test Circuits and Waveforms

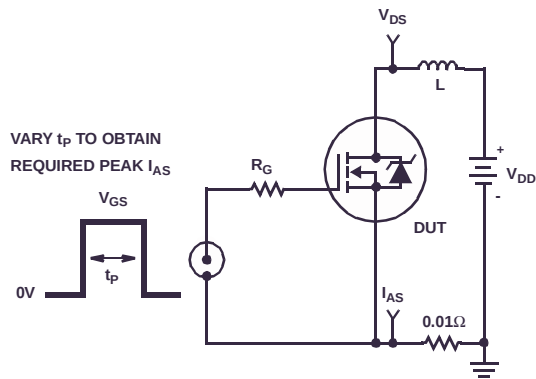


Figure 15. Unclamped Energy Test Circuit

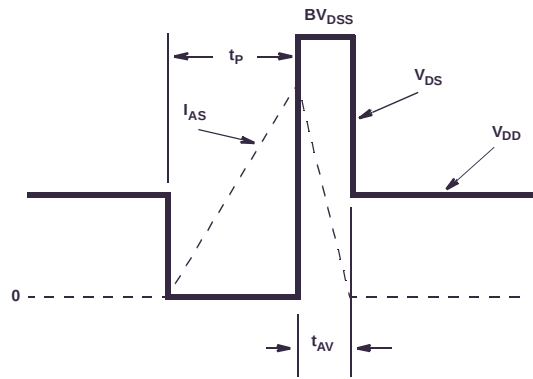


Figure 16. Unclamped Energy Waveforms

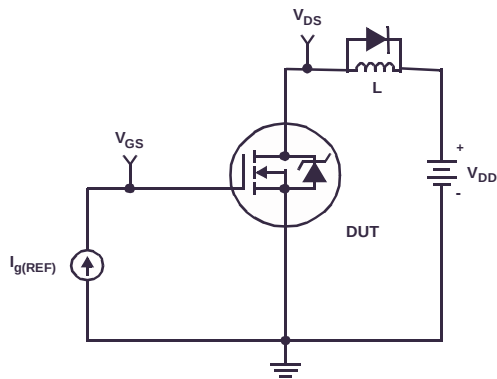


Figure 17. Gate Charge Test Circuit

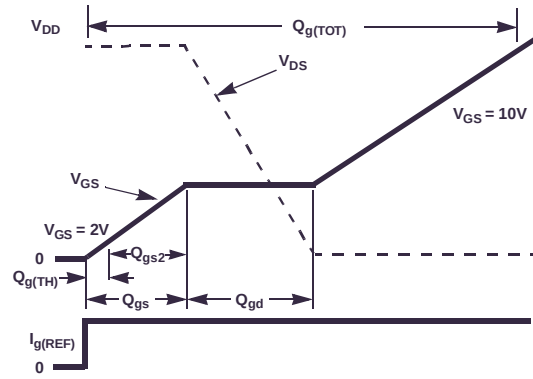


Figure 18. Gate Charge Waveforms

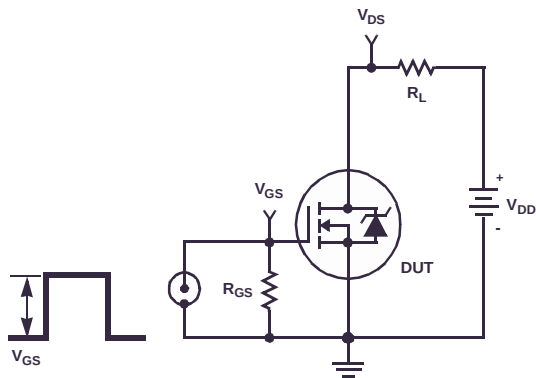


Figure 19. Switching Time Test Circuit

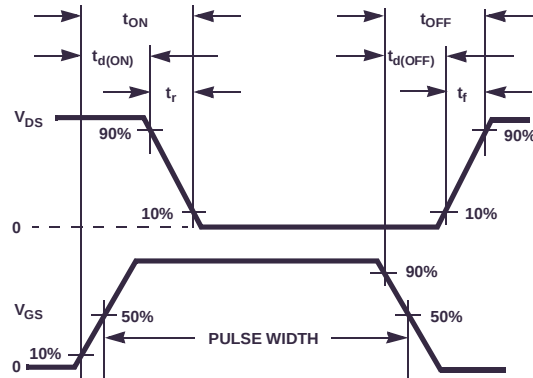


Figure 20. Switching Time Waveforms

Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A ($^{\circ}\text{C}$), and thermal resistance $R_{\theta JA}$ ($^{\circ}\text{C/W}$) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}} \quad (\text{EQ. 1})$$

In using surface mount devices such as the TO-263 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

1. Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
2. The number of copper layers and the thickness of the board.
3. The use of external heat sinks.
4. The use of thermal vias.
5. Air flow and board orientation.
6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeter square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\theta JA} = 26.51 + \frac{19.84}{(0.262 + \text{Area})} \quad (\text{EQ. 2})$$

Area in Inches Squared

$$R_{\theta JA} = 26.51 + \frac{128}{(1.69 + \text{Area})} \quad (\text{EQ. 3})$$

Area in Centimeters Squared

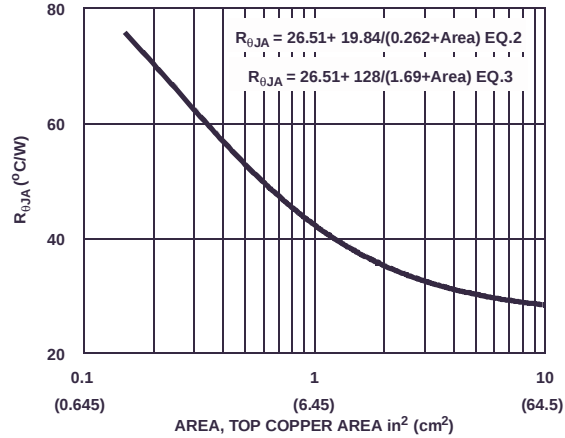


Figure 21. Thermal Resistance vs Mounting Pad Area

PSPICE Electrical Model

.SUBCKT FDB3682 2 1 3 ; rev May 2002
 CA 12 8 4e-10
 Cb 15 14 5.5e-10
 Cin 6 8 1.22e-9

Dbody 7 5 DbodyMOD
 Dbreak 5 11 DbreakMOD
 Dplcap 10 5 DplcapMOD

Ebreak 11 7 17 18 108
 Eds 14 8 5 8 1
 Egs 13 8 6 8 1
 Esg 6 10 6 8 1
 Evthres 6 21 19 8 1
 Evtemp 20 6 18 22 1

It 8 17 1

Lgate 1 9 5.96e-9
 Ldrain 2 5 1.0e-9
 Lsource 3 7 3.19e-9

RLgate 1 9 59.6
 RLdrain 2 5 10
 RLsource 3 7 31.9

Mmed 16 6 8 8 MmedMOD
 Mstro 16 6 8 8 MstroMOD
 Mweak 16 21 8 8 MweakMOD

Rbreak 17 18 RbreakMOD 1
 Rdrain 50 16 RdrainMOD 10.5e-3
 Rgate 9 20 1.86
 RSLC1 5 51 RSLCMOD 1.0e-6
 RSLC2 5 50 1.0e3
 Rsource 8 7 RsourceMOD 11.9e-3
 Rvthres 22 8 RvthresMOD 1
 Rvtemp 18 19 RvtempMOD 1
 S1a 6 12 13 8 S1AMOD
 S1b 13 12 13 8 S1BMOD
 S2a 6 15 14 13 S2AMOD
 S2b 13 15 14 13 S2BMOD

Vbat 22 19 DC 1

ESLC 51 50 VALUE={{(V(5,51)/ABS(V(5,51)))*(PWR(V(5,51)/(1e-6*70),2.5))}}

.MODEL DbodyMOD D (IS=2.4E-12 RS=4.4e-3 TRS1=2.0e-3 TRS2=4.5e-7
 + CJO=9e-10 M=0.57 TT=2.9e-8 XTI=4.0)

.MODEL DbreakMOD D (RS=0.6 TRS1=1.4e-3 TRS2=-5.0e-5)

.MODEL DplcapMOD D (CJO=2.7e-10 IS=1.0e-30 N=10 M=0.56)

.MODEL MstroMOD NMOS (VTO=4.16 KP=32 IS=1e-30 N=10 TOX=1 L=1u W=1u)

.MODEL MmedMOD NMOS (VTO=3.48 KP=2.7 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=1.86)

.MODEL MweakMOD NMOS (VTO=2.97 KP=0.04 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=18.6 RS=0.1)

.MODEL RbreakMOD RES (TC1=1.05e-3 TC2=-1.1e-8)

.MODEL RdrainMOD RES (TC1=1.6e-2 TC2=4e-5)

.MODEL RSLCMOD RES (TC1=3.0e-3 TC2=2.9e-6)

.MODEL RsourceMOD RES (TC1=1e-3 TC2=1e-6)

.MODEL RvthresMOD RES (TC1=-4.1e-3 TC2=-1.4e-5)

.MODEL RvtempMOD RES (TC1=-3.5e-3 TC2=1.3e-6)

.MODEL S1AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-5.0 VOFF=-2.0)

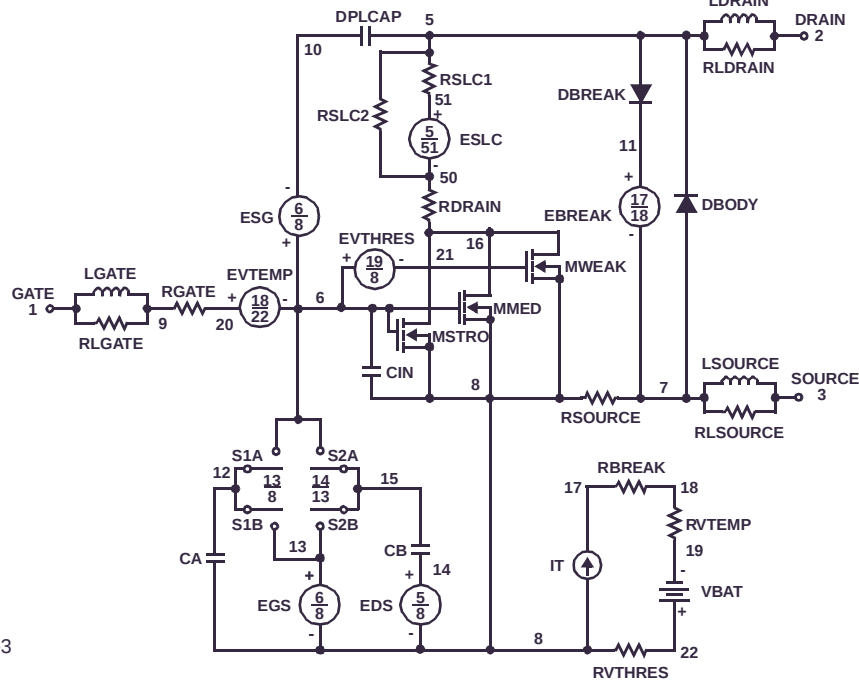
.MODEL S1BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-2.0 VOFF=-5.0)

.MODEL S2AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-0.4 VOFF=0.3)

.MODEL S2BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=0.3 VOFF=-0.4)

.ENDS

Note: For further discussion of the PSPICE model, consult **A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options**; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley.



SPICE Thermal Model

REV 20 May 2002

FDB3682_JC TH TL

CTHERM1 TH 6 1.6e-3
 CTHERM2 6 5 4.5e-3
 CTHERM3 5 4 5.0e-3
 CTHERM4 4 3 8.0e-3
 CTHERM5 3 2 8.2e-3
 CTHERM6 2 TL 4.7e-2

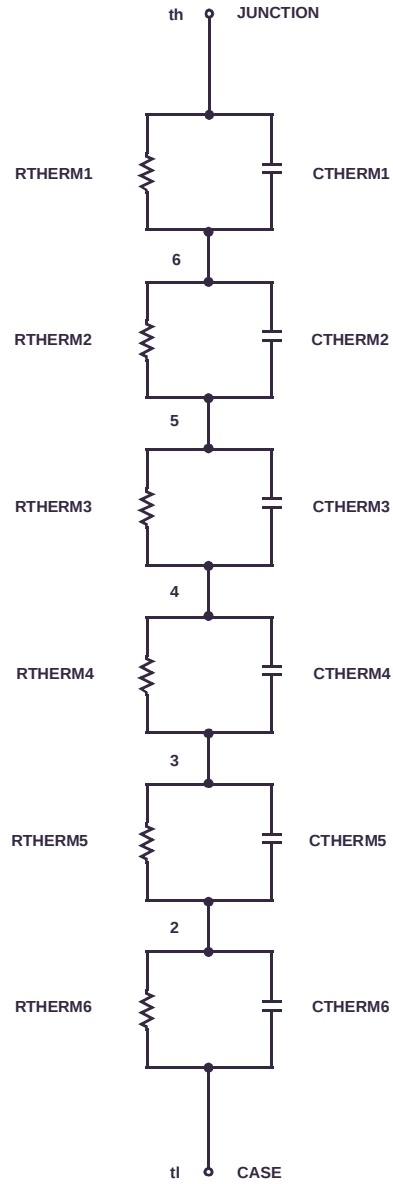
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 RTHERM2 6 5 7.9e-2
 RTHERM3 5 4 9.5e-2
 RTHERM4 4 3 1.4e-1
 RTHERM5 3 2 2.9e-1
 RTHERM6 2 TL 6.7e-1

SABER Thermal Model

SABER thermal model FDB3682
 template thermal_model th tl
 thermal_c th, tl

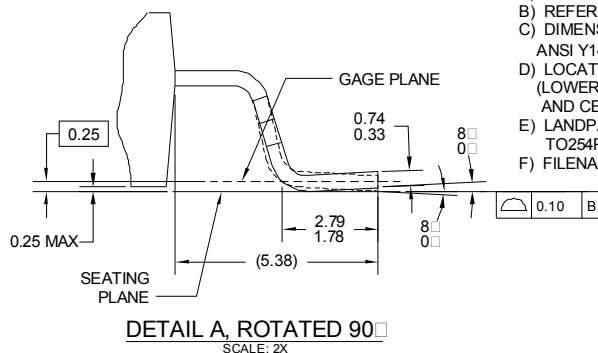
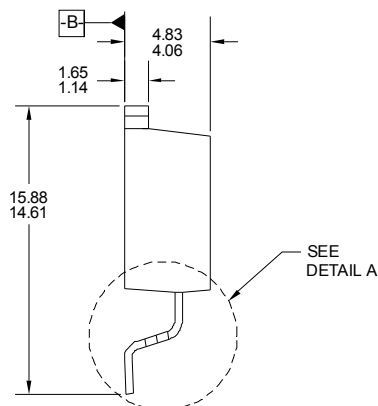
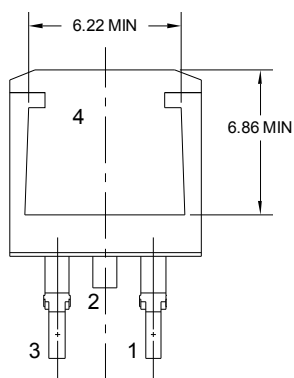
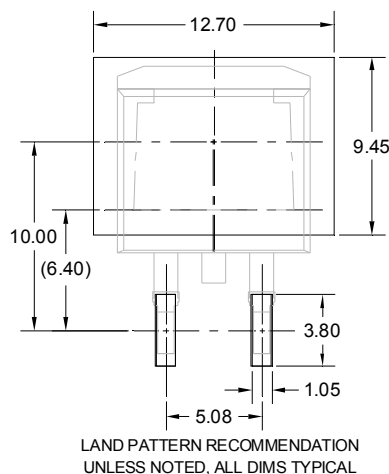
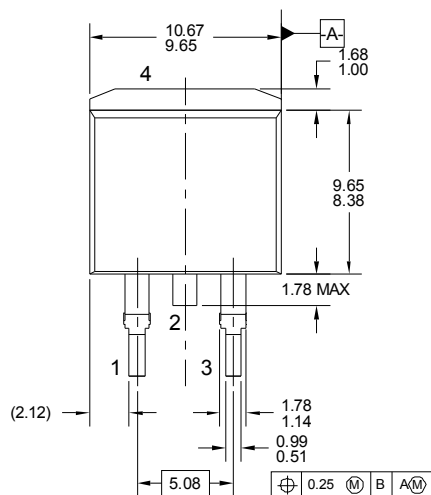
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  ctherm.ctherm2 6 5 =4.5e-3
  ctherm.ctherm3 5 4 =5.0e-3
  ctherm.ctherm4 4 3 =8.0e-3
  ctherm.ctherm5 3 2 =8.2e-3
  ctherm.ctherm6 2 tl =4.7e-2
```

```
rtherm.rtherm1 th 6 =3.3e-2
rtherm.rtherm2 6 5 =7.9e-2
rtherm.rtherm3 5 4 =9.5e-2
rtherm.rtherm4 4 3 =1.4e-1
rtherm.rtherm5 3 2 =2.9e-1
rtherm.rtherm6 2 tl =6.7e-1
}
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Mechanical Dimensions

D2-PAK

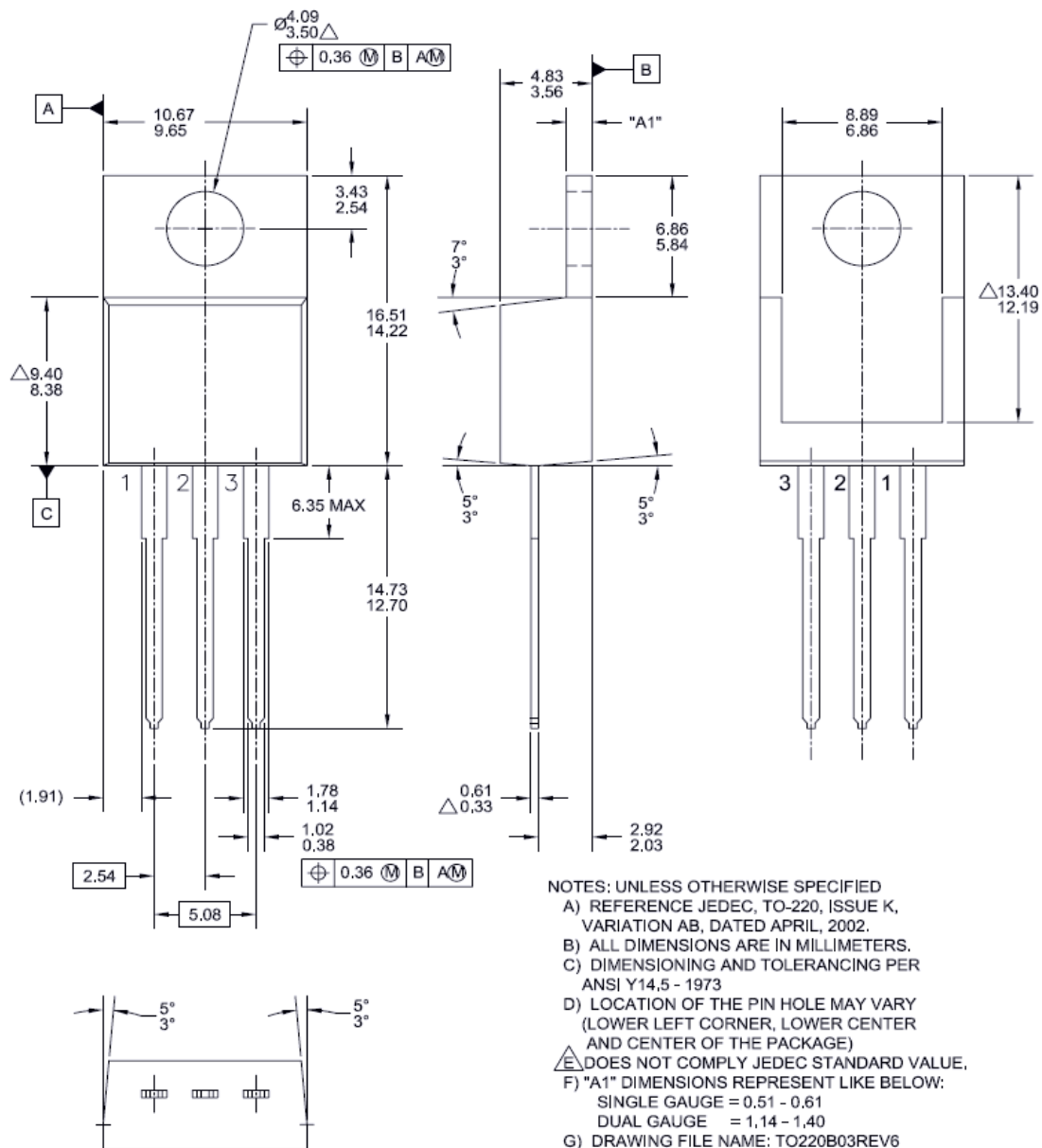


- NOTES: UNLESS OTHERWISE SPECIFIED
A) ALL DIMENSIONS ARE IN MILLIMETERS.
B) REFERENCE JEDEC, TO-263, VARIATION AB.
C) DIMENSIONING AND TOLERANCING PER ANSI Y14.5M - 1994.
D) LOCATION OF THE PIN HOLE MAY VARY (LOWER LEFT CORNER, LOWER CENTER AND CENTER OF THE PACKAGE).
E) LANDPATTERN RECOMMENDATION PER IPC TO254P1524X482-3N
F) FILENAME: TO263A02REV6

Dimensions in Millimeters

Mechanical Dimensions

TO-220



Dimensions in Millimeters

2Cool™
 AccuPower™
 AX-CAP®*
 BitSiC™
 Build it Now™
 CorePLUS™
 CorePOWER™
 CROSSVOL™
 CTL™
 Current Transfer Logic™
 DEUXPEED®
 Dual Cool™
 EcoSPARK®
 EfficientMax™
 ESBC™
F®
 Fairchild®
 Fairchild Semiconductor®
 FACT Quiet Series™
 FACT®
 FAST®
 FastvCore™
 FFTBench™



PowerTrench[®]
PowerXS[™]
Programmable Active Droop[™]
QFET[®]
QS[™]
Quiet Series[™]
RapidConfigure[™]
[™]
Saving our world, 1mW/W/kW at a time[™]
SignalWise[™]
SmartMax[™]
SMART Series[™]
Solutions for Your Success[™]
SPM[®]
STEALTH[™]
SuperFET[®]
SuperSOT[™]-3
SuperSOT[™]-6
SuperSOT[™]-8
SupreMOS[®]
SynvFET[™]



Sync-Lock™
 SYSTEM GENERAL®
 TinyBoost™
 TinyBuck™
 TinyCalc™
 TinyLogic®
 TINYOPTO™
 TinyPower™
 TinyPWM™
 TinyWire™
 TranSiC®
 TriFault Detect™
 TRUECURRENT®
 SerDes™
 UHC®
 Ultra FRFET™
 UniFET™
 VCX™
 VisualMax™
 VoltagePlus™
 xS™

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2. A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

ANTI-COUNTERFEITING POLICY

Fairchild Semiconductor Corporation's Anti-Counterfeiting Policy. Fairchild's Anti-Counterfeiting Policy is also stated on our external website, www.Fairchildsemi.com, under Sales Support.

Counterfeiting of semiconductor parts is a growing problem in the industry. All manufactures of semiconductor products are experiencing counterfeiting of their parts. Customers who inadvertently purchase counterfeit parts experience many problems such as loss of brand reputation, substandard performance, failed application, and increased cost of production and manufacturing delays. Fairchild is taking strong measures to protect ourselves and our customers from the proliferation of counterfeit parts. Fairchild strongly encourages customers to purchase Fairchild parts either directly from Fairchild or from Authorized Fairchild Distributors who are listed by country on our web page cited above. Products customers buy either from Fairchild directly or from Authorized Fairchild Distributors are genuine parts, have full traceability, meet Fairchild's quality standards for handling and storage and provide access to Fairchild's full range of up-to-date technical and product information. Fairchild and our Authorized Distributors will stand behind all warranties and will appropriately address and warranty issues that may arise. Fairchild will not provide any warranty coverage or other assistance for parts bought from Unauthorized Sources. Fairchild is committed to combat this global problem and encourage our customers to do their part in stopping this practice by buying direct or from authorized distributors.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative / In Design	Datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	Datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	Datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. 164

Данный компонент на территории Российской Федерации

Вы можете приобрести в компании MosChip.

Для оперативного оформления запроса Вам необходимо перейти по данной ссылке:

<http://moschip.ru/get-element>

Вы можете разместить у нас заказ для любого Вашего проекта, будь то серийное производство или разработка единичного прибора.

В нашем ассортименте представлены ведущие мировые производители активных и пассивных электронных компонентов.

Нашей специализацией является поставка электронной компонентной базы двойного назначения, продукции таких производителей как XILINX, Intel (ex.ALTERA), Vicor, Microchip, Texas Instruments, Analog Devices, Mini-Circuits, Amphenol, Glenair.

Сотрудничество с глобальными дистрибьюторами электронных компонентов, предоставляет возможность заказывать и получать с международных складов практически любой перечень компонентов в оптимальные для Вас сроки.

На всех этапах разработки и производства наши партнеры могут получить квалифицированную поддержку опытных инженеров.

Система менеджмента качества компании отвечает требованиям в соответствии с ГОСТ Р ИСО 9001, ГОСТ РВ 0015-002 и ЭС РД 009

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